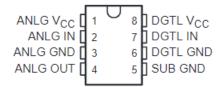
TL1591 SAMPLE-AND-HOLD CIRCUIT FOR CCD IMAGERS

SOCS026B - SEPTEMBER 1989 - REVISED JUNE 1994

- 15-MHz Sampling Rate
- 30-ns Acquisition Time
- . Diode-Bridge Switch
- 25-MHz Bandwidth
- Low-Voltage Supply

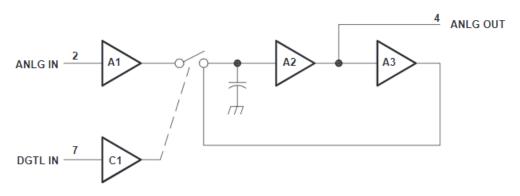
P OR PS PACKAGE (TOP VIEW)



description

The TL1591 is a monolithic integrated sample-and-hold circuit that uses the BiFET process with Schottky-barrier diodes and is designed for use with CCD area imagers. This device consists of an ultra-fast input-buffer amplifier, a digital-controlled diode-bridge switch, and a high-impedance output buffer amplifier. The electronic switch is controlled by an LS-TTL-compatible logic input.

functional block diagram





This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, precautions should be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits. During storage or handling, the device leads should be shorted together or the device should be placed in

conductive foam. In a circuit, unused inputs should always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground. Specific guidelines for handling devices of this type are contained in the publication *Guidelines for Handling Electrostatic-Discharge-Sensitive (ESDS) Devices and Assemblies* available from Texas Instruments.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 80°C POWER RATING		
Р	1000 mW	8.0 mW/°C	560 mW		
PS	725 mW	5.8 mW/°C	406 mW		

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.5	V
High-level input voltage, VIH	2			V
Low-level input voltage, V _{IL}			0.8	V
Peak-to-peak input voltage, V _{I(PP)}			8.0	V
Operating free-air temperature, T _A	-25		80	°C

electrical characteristics over ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
			TEST CONDITIONS		1117		
V_{IK}	Input clamp voltage					-1.5	V
V _{O(PP)}	Peak-to-peak output voltage				1.1		V
lн	High-level input current	V _{CC} = 5.5 V,	V _{IH} = 2.7 V			20	∞A
Iμ	Low-level input current	V _{CC} = 5.5 V,	V _{IL} = 0.4 V		-0.28	-0.4	mΑ
I _O	Output current				0.6		mΑ
Icc	Supply current	V _{CC} = 5.5 V			15	20	mA
η	Input resistance				10		kΩ
ro	Output resistance				50		Ω

operating characteristics

PARAMETER		MIN	түр‡	MAX	UNIT
	Linearity		0.7%	2%	
A _V	Voltage amplification		8.0	0.9	V/V
	Sample-to-hold offset error		15		mV
	Sample-mode offset error	-150	-50	50	mV
	Hold-mode feedthrough			-50	dB
	Hold-mode droop			100	∞V/∞s

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.